

# **Modification of Thick-film Conductors Used in IP Technology For Reduction of Warpage during Co-firing of LTCC (Low Temperature Co-fired Ceramic) Technology**

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Thick-film Group**

[lpmwww.epfl.ch](http://lpmwww.epfl.ch)

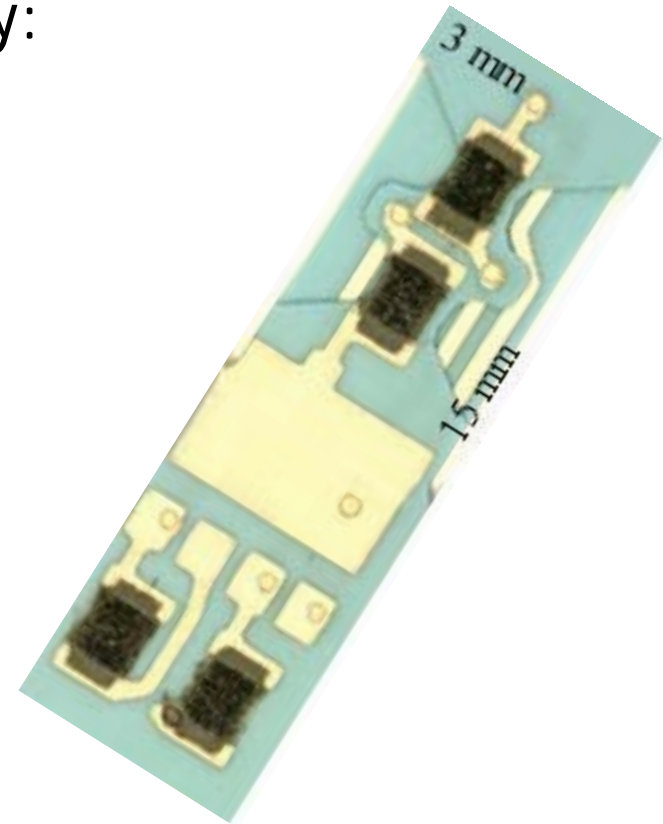


## PURPOSE OF THE PRESENTATION

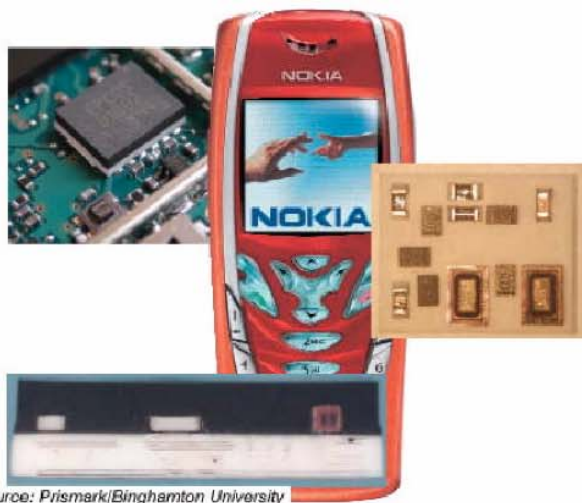
➔ Introduction to LTCC Technology:  
*General aspects*

➔ Materials compatibility issues:  
*Chemical issues*  
*Physical issues\**  
*Reliability issues for devices*

➔ Ensuring reliability:  
*Modification of commercial pastes*



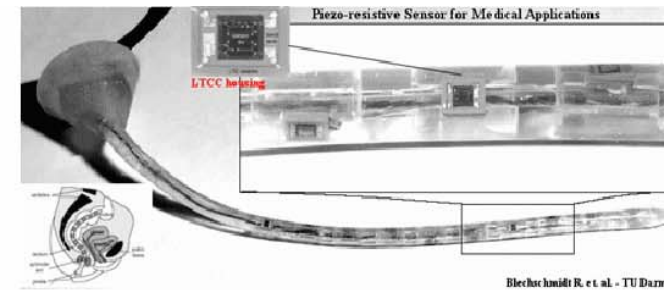
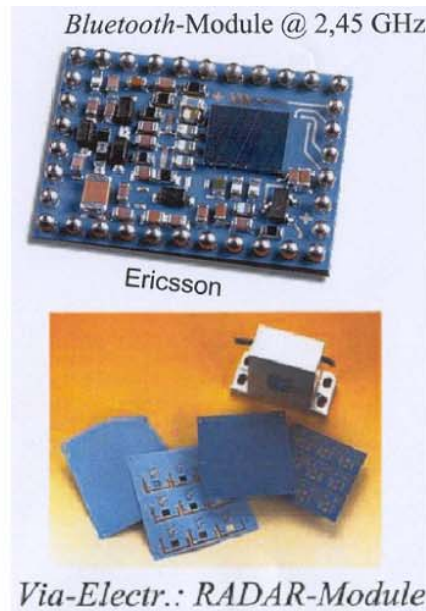
Application areas of LTCC technology have diversified



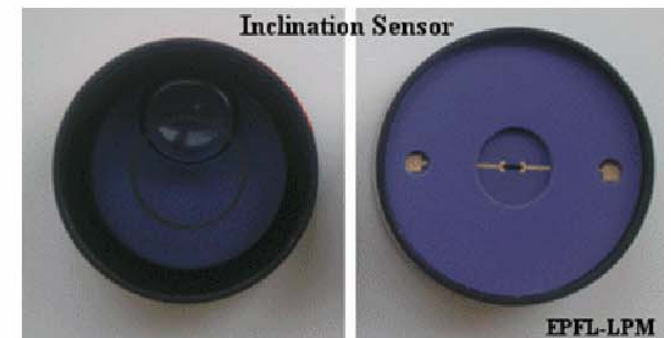
Source: Prismark/Binghamton University

**EPCOS FRONT END MODULE**

- Key component in new Nokia mobile phone architecture
- Integrates duplexer, switching, LC and SAW filters
- Analysis of LTCC integrates passives and SAW filter packages



Blechnicki R. et al. - TU Darm

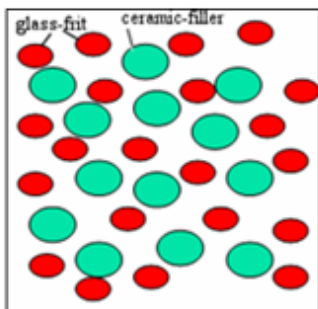
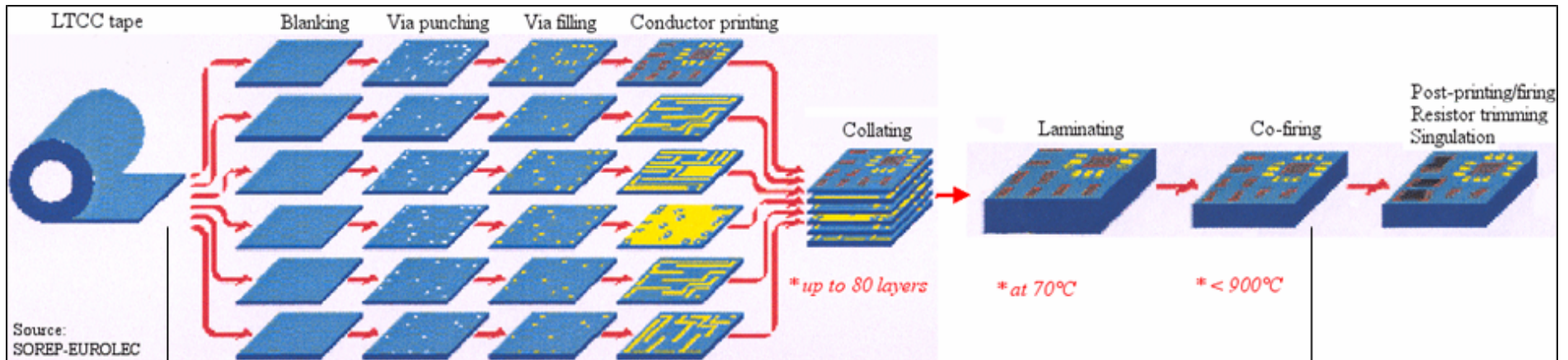


# INTRODUCTION: LTCC MATERIALS SYSTEM

Introduction

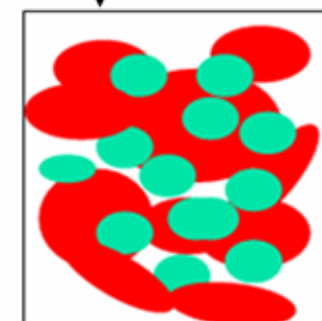
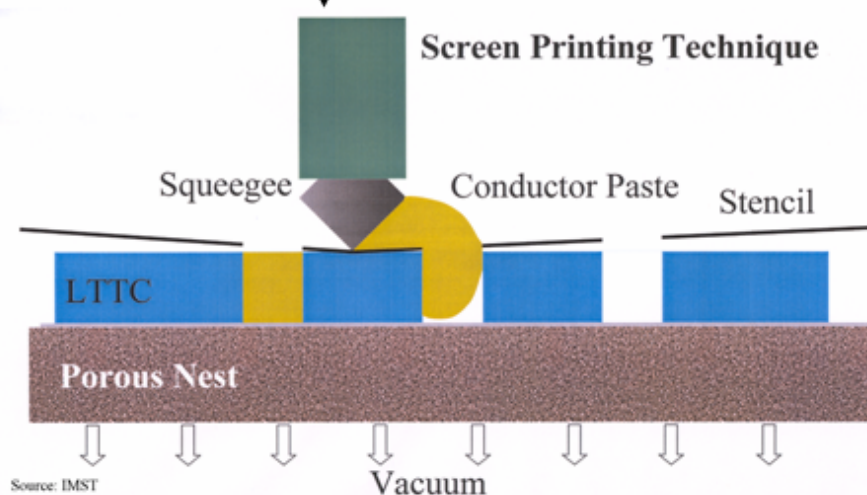
Compatibility

Modification



**Glass-frit:** low firing T  
**Filler:** dimensional stability

... blended in organic-vehicle  
& cast on mylar sheets



# ADVANTAGES OF LTCC TECHNOLOGY

Introduction

Compatibility

Modification

➔ Excellent dielectric properties for high frequencies

➔ Ease of machinability of tapes

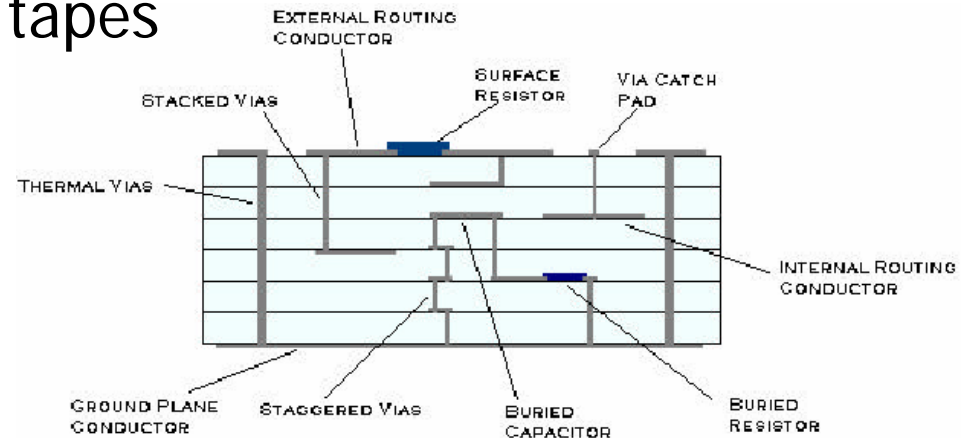
➔ Cost effective

➔ High density packaging

➔ Excellent chemical / thermal stability

➔ Hermeticity of the structures

➔ Mechanical and electrical functions in one system

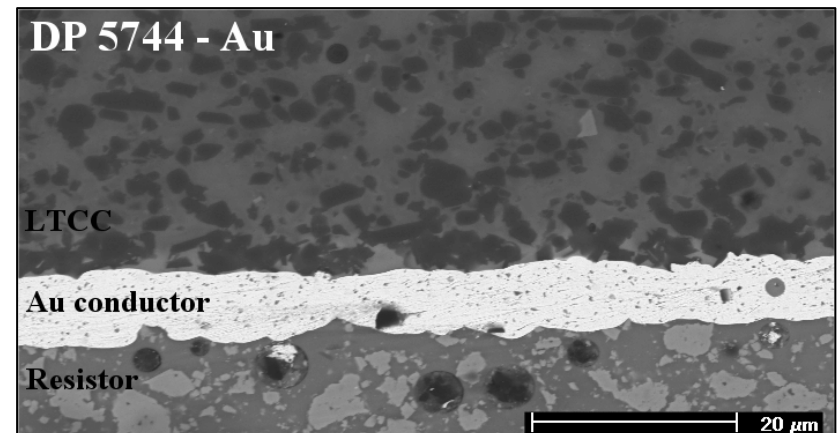
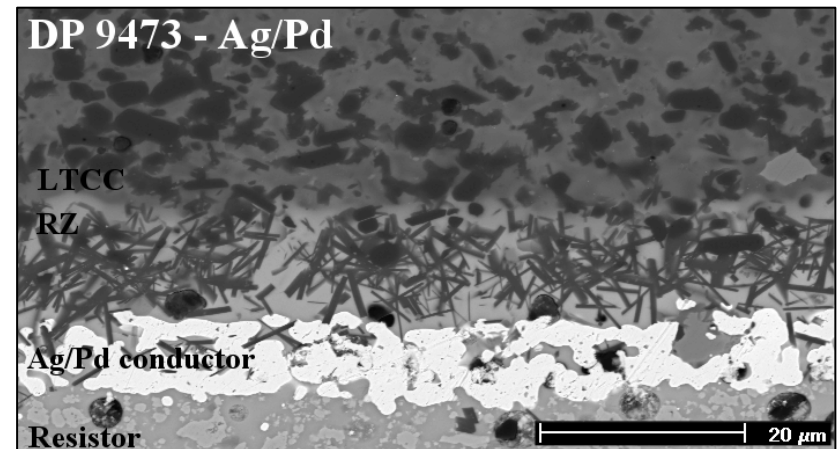


## CHEMICAL ISSUES

Related to materials interaction during co-firing:

- Pronounced over  $T_g^*$
- Enhanced by concentration gradient of certain species in different components

\* *Glass in LTCC softens over  $T_g$ , wets the ceramic fillers, fills the interparticle-regions & rearranges them*



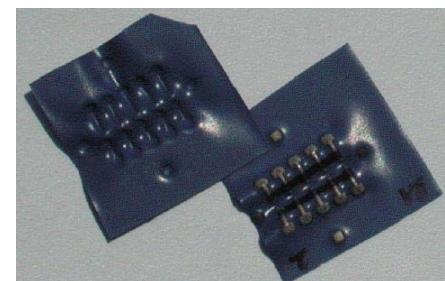
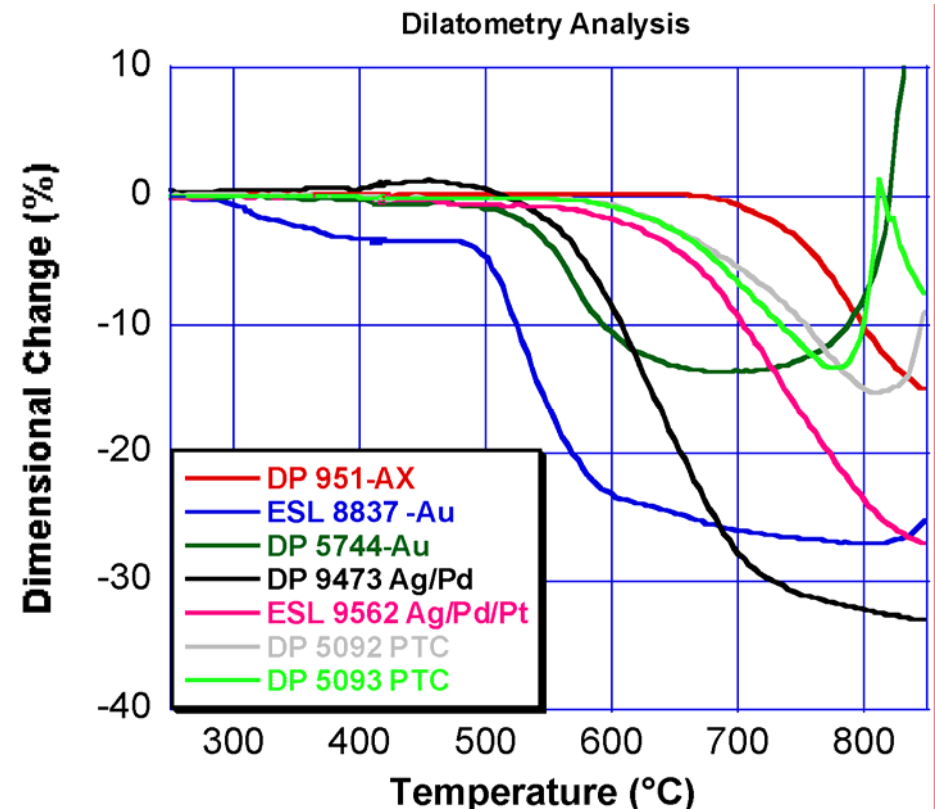
## PHYSICAL ISSUES

Arises from the difference in thermo-mechanical properties of co-fired components & de-gassing.

They are mostly observed as warpage, curling due to:

1. early sintering
2. higher extent of shrinkage

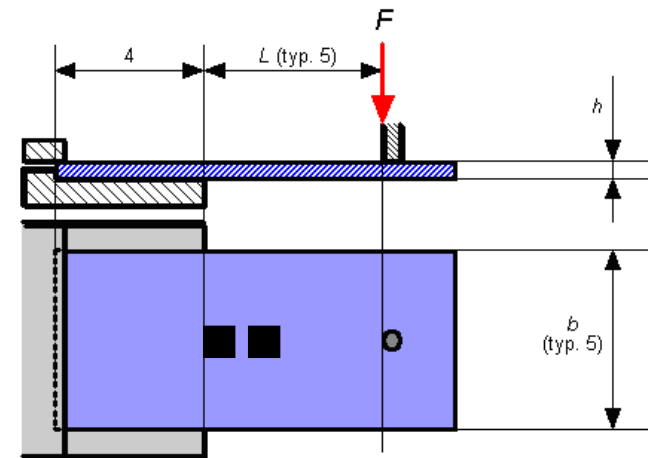
of thick-film components compared to LTCC



## RELIABILITY OF DEVICES

Motivation of the study is driven by fabrication of millinewton force sensor\* (MFS).

\* *The beam of the MFS, where the piezoresistors pastes are screen-printed and the force is applied must be **flat & warpage-free** following co-firing*



$$\text{Signal} = \varepsilon_{\max} G_f$$

$$\varepsilon = (6FL) / (bh^2)E$$

Figure of merit:  $h$

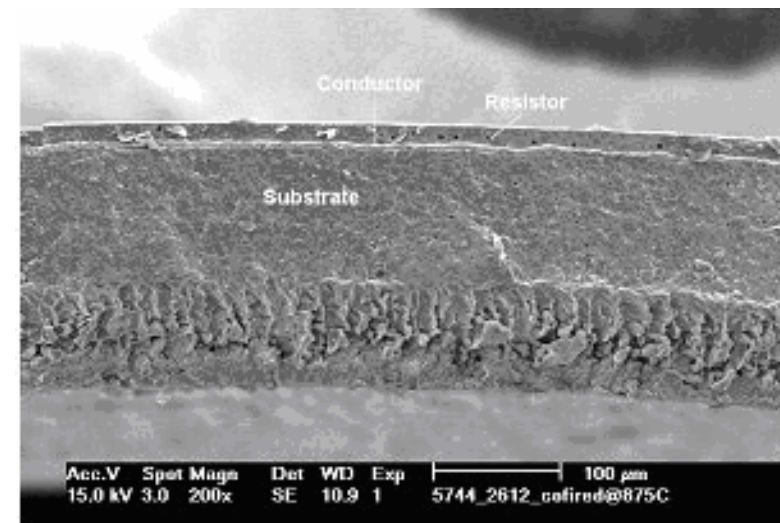
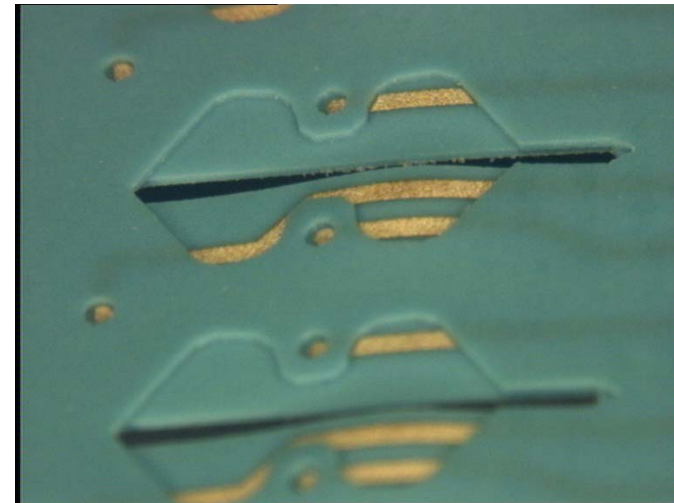
Limitation: *warpage*



## MODIFICATION OF PASTES

With the objective of reducing warpage in the co-fired module of LTCC+thick-film components by:

*Matching the shrinkage rate & extent of commercial conductors with LTCC*



# MODIFYING PASTES USING ADDITIVES

Introduction

Compatibility

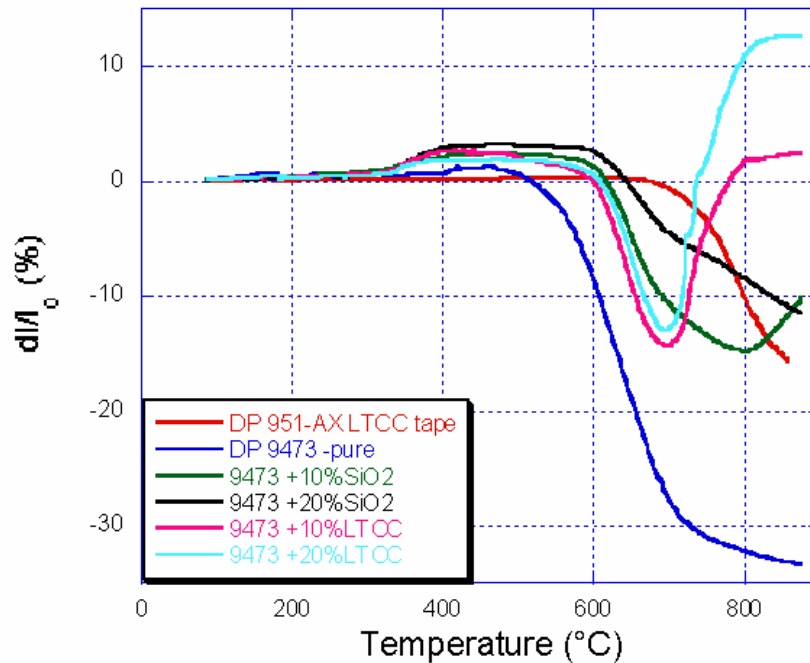
Modification

Paste	Specification	Additive	
		SiO <sub>2</sub> *	LTCC
DP 9473	Ag/Pd	10%	10%
		20%	20%
ESL 9562**	Ag/Pd/Pt	10%	10%
		20%	20%

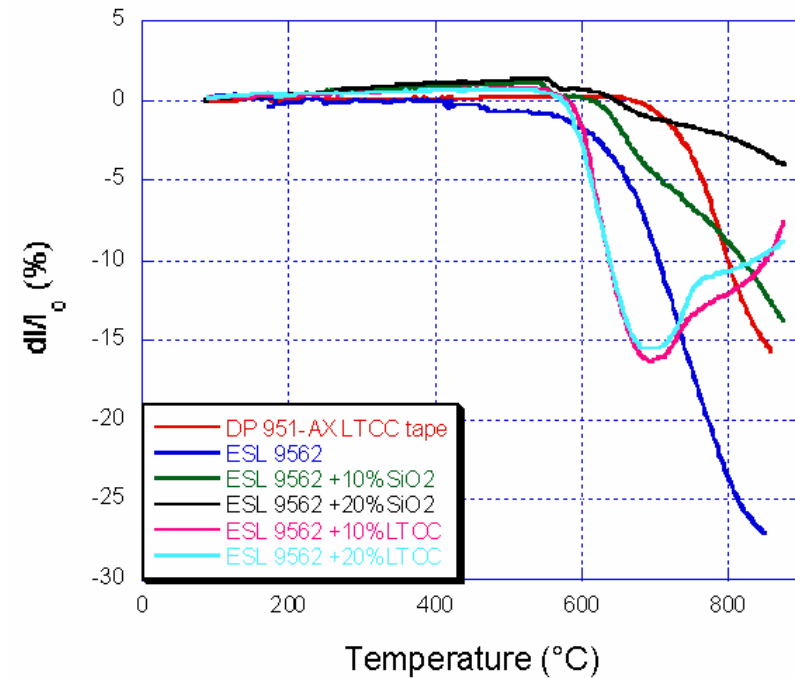
\*SiO<sub>2</sub>: Sihelco, Sikron B 600

\*\* Fritless conductor with Cu additions (Ag/Pd-16)

Shrinkage Match Analysis with DP 9473



Shrinkage Match Analysis with DP 9562

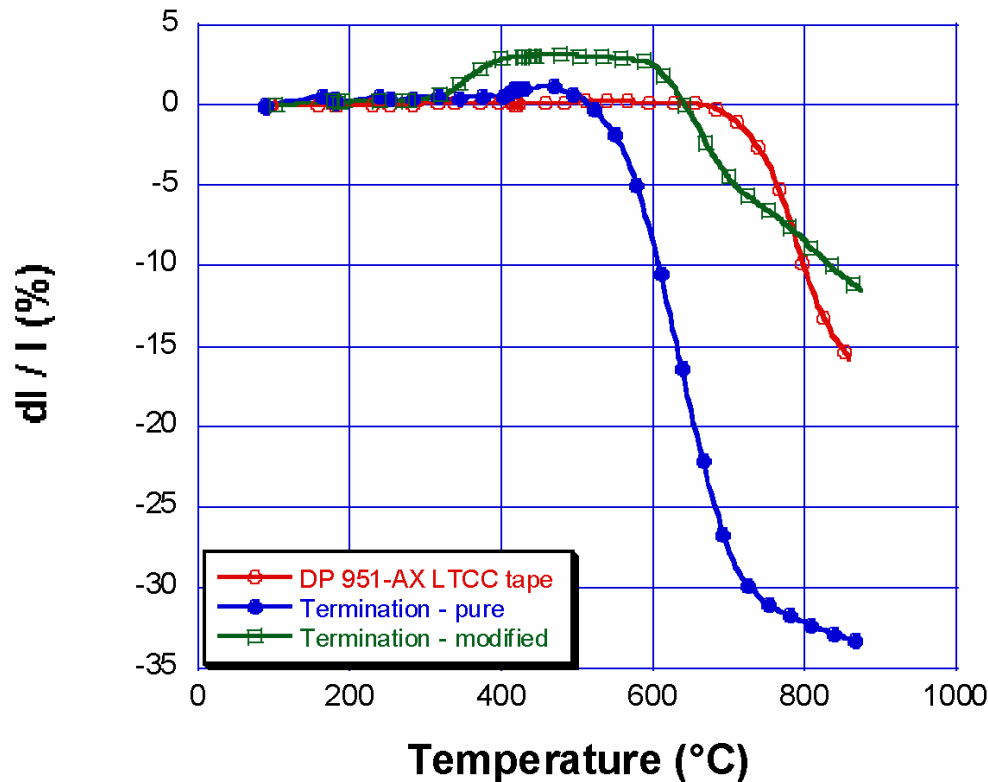


# RESULTS I SHRINKAGE MATCH

Introduction

Compatibility

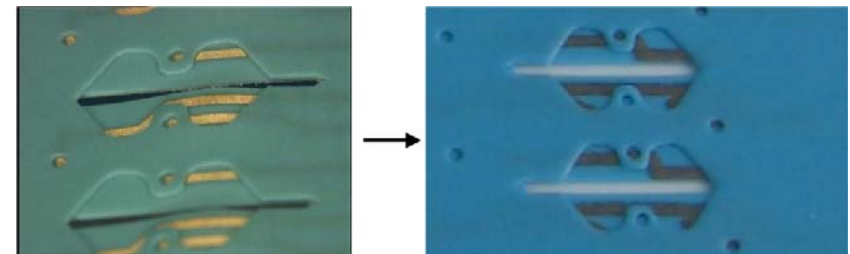
Modification



The (onset) sintering temperature of the conductor has been shifted up to that of LTCC

Paste (ratio of doping)	$T_{shr.}^+$ (°C)	%Shrinkage <sup>++</sup> (-)
<b>DP 9473</b>	516	23
DP 9473 + 10%	618	7.7
DP 9473 + 20%	644	2.3
<b>ESL 9562</b>	430	5.5
ESL 9562 + 10%	615	3
ESL 9562 + 20%	646	0.7

$T_{shr.}^+$ : Onset temperature of shrinkage of the paste ( $\Delta l/l < 0$ )  
%Shrinkage<sup>++</sup>: Amount of paste shrinkage at the onset temperature of the tape shrinkage (670°C).



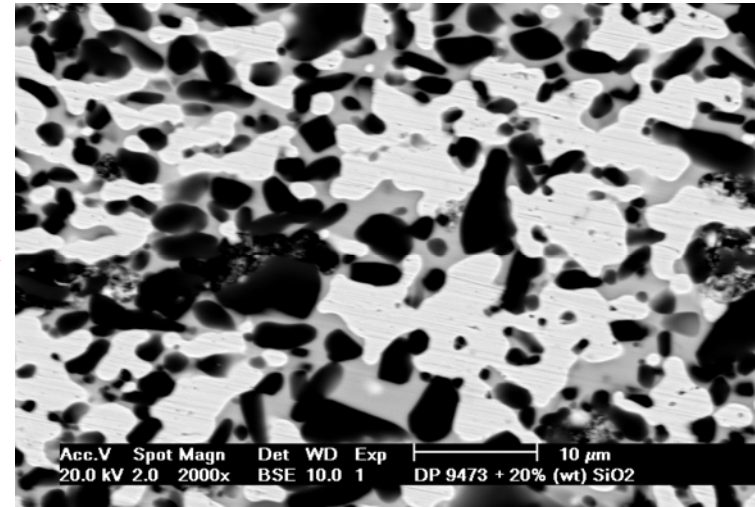
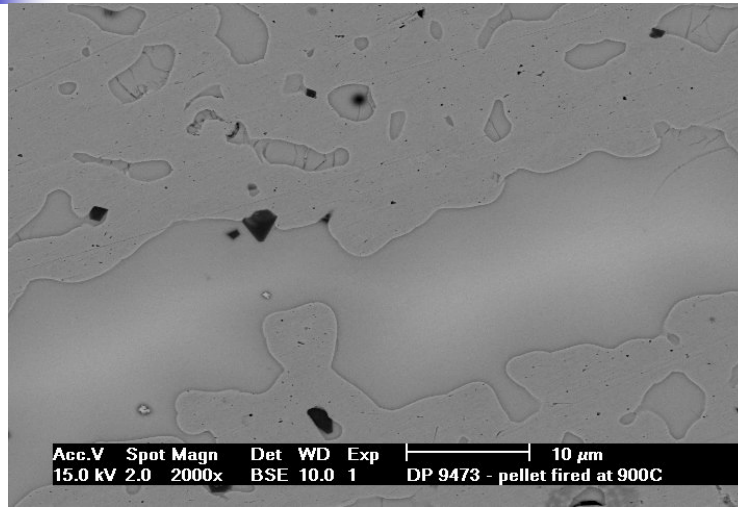
# RESULTS II MICROSTRUCTURE

Introduction

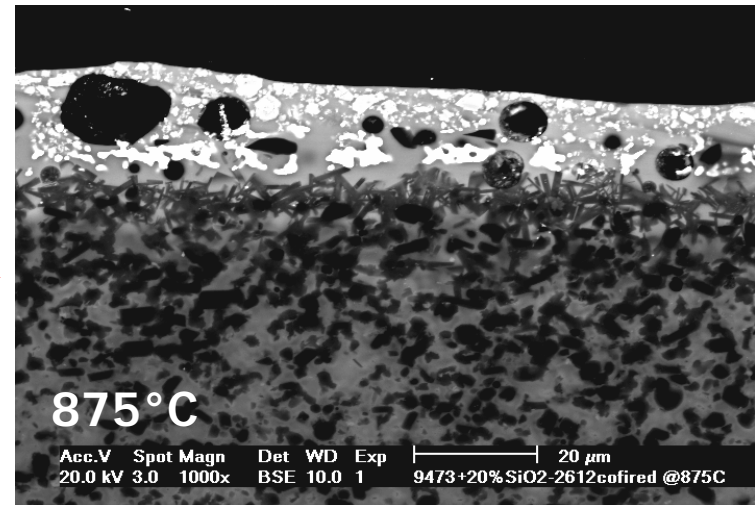
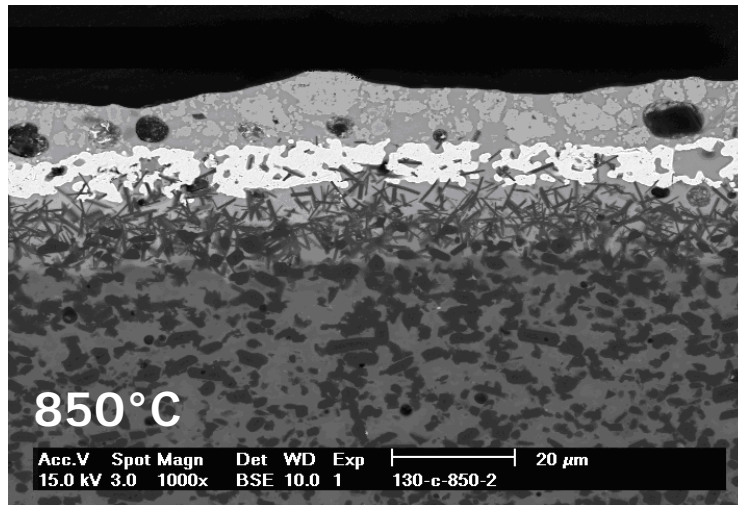
Compatibility

Modification

P  
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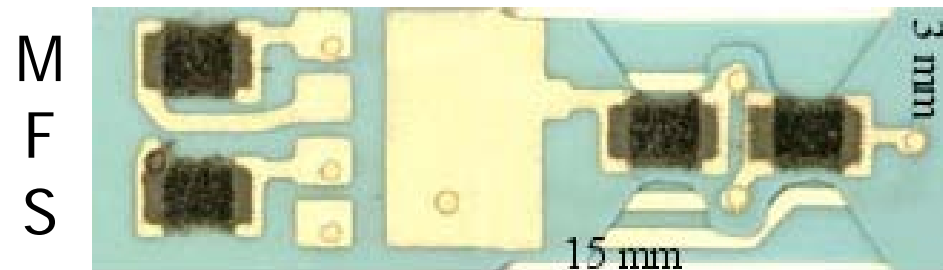
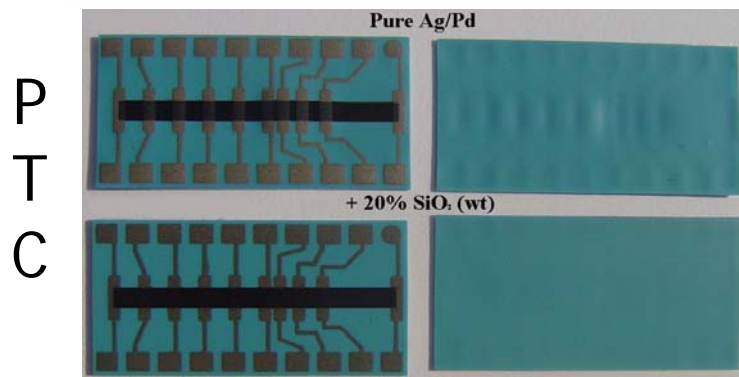
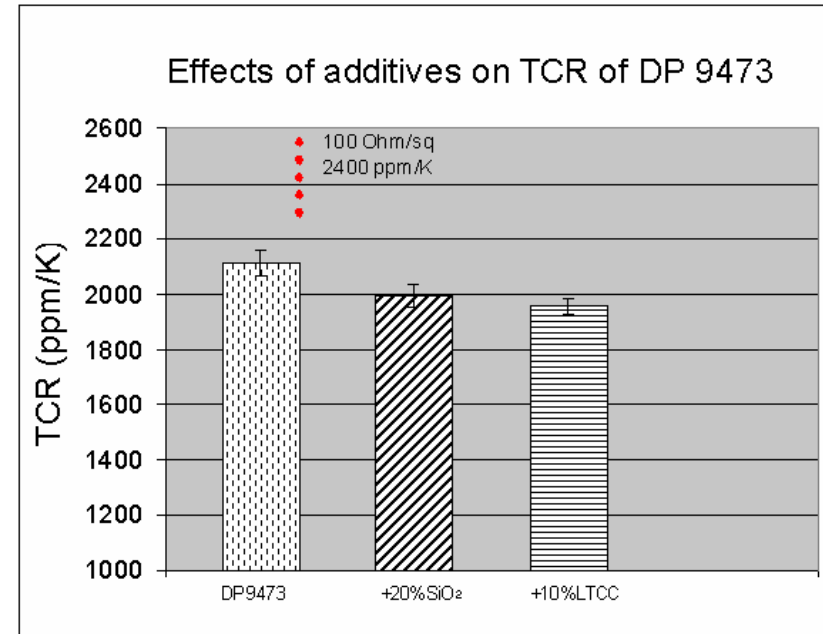
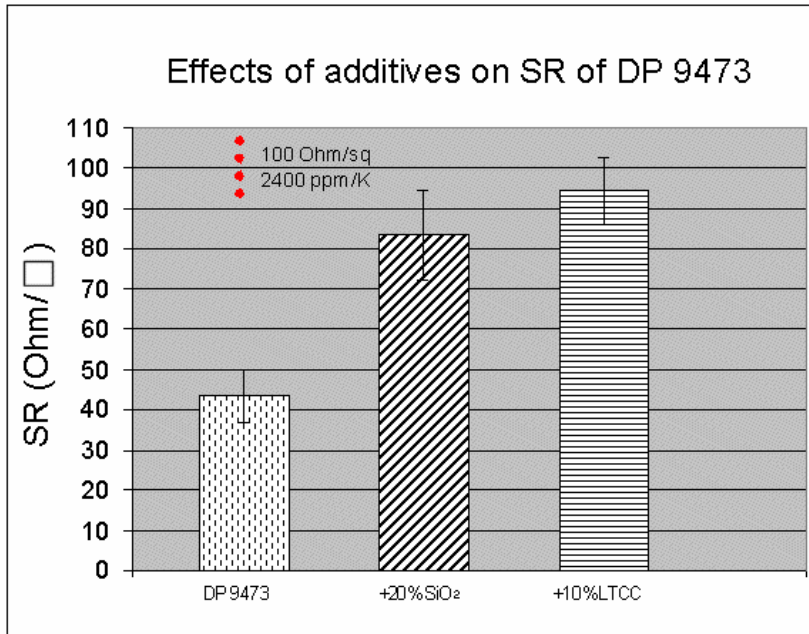


# RESULTS III ELECTRICAL PROP. & DEVICE

Introduction

Compatibility

Modification





## CONCLUSIONS

→ For increased reliability, materials incompatibility issues must be well-controlled:

*chemical interaction & thermo-mechanical differences between materials*

→ Differential shrinkage of components are shown to be matched efficiently, avoiding warpage, curling, etc...by:

*mixing the commercial conductors with selected additives*

→ The effect of modification has been verified to be close to expected values of PTC resistors

*favors the application of the technology in multi-disciplinary areas very soon*